

積體電路之暫態觸發門鎖效應 Transient-Induced Latchup in CMOS Integrated Circuits

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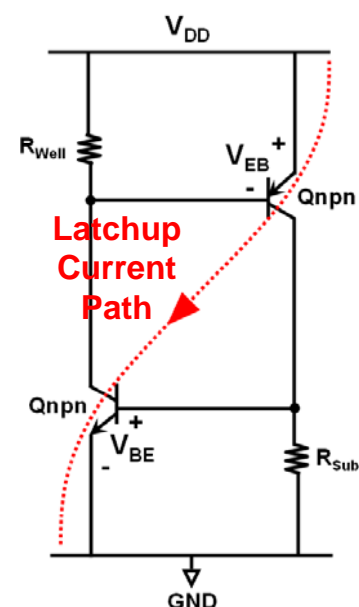
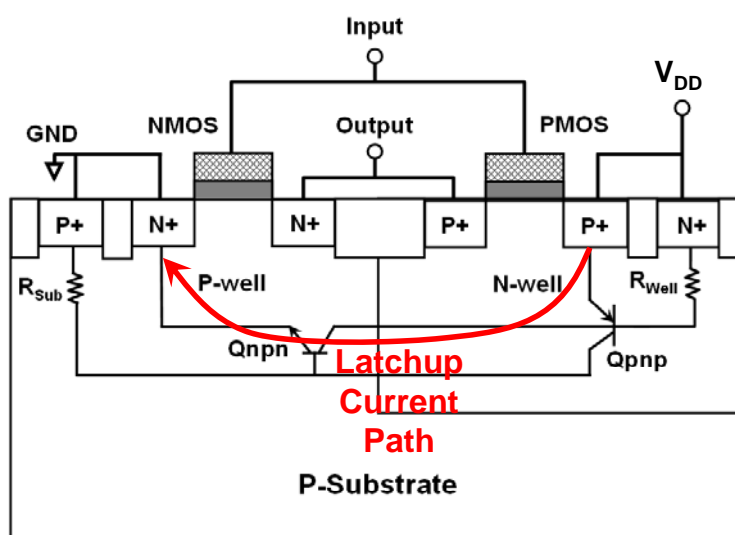
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I. INTRODUCTION

1. Background of TLU

- TLU represents a latchup event initiated by a fast “transient” triggering mode.



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